



ASSOCIATION CONNECTING
ELECTRONICS INDUSTRIES

IPC-SM-780

Component Packaging
and Interconnecting
with Emphasis on
Surface Mounting

ANSI/IPC-SM-780

July 1988

A guideline developed by IPC

Table of Contents

1.0 INTRODUCTION	1	3.1 System Design Sequence	5
1.1 Scope.....	1	3.1.1 System Requirements	5
1.2 Purpose	1	3.1.2 Circuit Requirements.....	5
1.3 Classification.....	1	3.1.3 Performance Considerations.....	6
1.4 Terms and Definitions	1	3.1.4 Reliability Considerations	6
1.4.1 Castellations.....	1	3.1.5 System Integration.....	7
1.4.2 Chip Carrier.....	1	3.2 Technology Trends	9
1.4.3 Coefficient of Thermal Expansion Mismatch ..	1	3.2.1 Package Technology	10
1.4.4 Component.....	2	3.2.2 Interconnect Technology	10
1.4.5 Component Mounting Site	2	3.2.3 Size Considerations	11
1.4.6 Constraining Core.....	2	3.3 Packaging/Interconnection Assembly Implementation Techniques.....	11
1.4.7 Double-Sided Assembly	2	3.3.1 Comparisons	12
1.4.8 Dual In-Line Package.....	2	3.3.2 Size	12
1.4.9 Flat Pack	2	3.3.3 Through-Hole Mounting Technology	13
1.4.10 Footprint	2	3.3.4 Surface Mount Technology	14
1.4.11 Grid	2	3.3.5 Intermixed Technology.....	16
1.4.12 Integrated Circuit (IC).....	2	3.3.6 Other Considerations	17
1.4.13 Land Pattern	2	4.0 ELECTRONIC COMPONENT TYPES AND INTERCONNECTION DEVICES	17
1.4.14 Leaded Chip Carrier.....	2	4.1 General Considerations	17
1.4.15 Leadless Chip Carrier.....	2	4.1.1 Lead/Termination Finishes	17
1.4.16 Mixed Mounting Technology.....	2	4.1.2 Component Handling	18
1.4.17 Packaging and Interconnecting Structure	2	4.1.3 Precleaning Techniques	20
1.4.18 Primary Side	2	4.2 Discrete Component Types	20
1.4.19 Secondary Side	2	4.2.1 Axial Leaded	20
1.4.20 Single In-Line Package	2	4.2.2 Radial Leaded Components	20
1.4.21 Single-Sided Assembly.....	2	4.2.3 Chip Components (Leaded and Leadless).....	20
1.4.22 Supporting Plane	2	4.2.4 Direct Deposition	22
1.4.23 Surface Mounting	2	4.2.5 Switches	23
1.4.24 Thermal Expansion Mismatch	2	4.2.6 Other Devices	23
1.4.25 Via Hole.....	2	4.3 Semiconductor Package Types.....	23
2.0 REFERENCE DOCUMENTS	3	4.3.1 Multileaded Radial Type Components.....	24
2.1 Institute for Interconnecting and Packaging Electronic Circuits (IPC).....	3	4.3.2 Small Outline Packages	24
2.2 Electronic Industries Association (EIA)	3	4.3.3 In-Line Packages Configurations	26
2.3 Military	3	4.3.4 Ribbon Multileaded Component Types (Flat Packs and Quad Packs).....	28
2.3.1 Standards	3	4.3.5 Chip Carriers (Leaded and Leadless)	29
2.3.2 Specifications	4	4.3.6 Grid Arrays	36
2.4 Federal	4	4.4 Sockets and Connectors	38
2.5 American National Standards Institute (ANSI)	4	4.4.1 Materials	38
3.0 COMPONENT PACKAGING AND INTERCONNECTION (CPI) IMPLEMENTATION CONCEPT	4	4.4.2 Lead Configuration and Spacing	38
		4.4.3 Socket Types.....	39

4.4.4	Connectors	41	6.2.3	Electrical Configuration	54
5.0	PACKAGING AND INTERCONNECTING STRUCTURE (P&IS) TYPE	42	6.2.4	Component Considerations	55
5.1	General Considerations	44	6.2.5	Cost Consideration	55
5.1.1	Categories	46	6.2.6	Design Checklist.....	55
5.1.2	Design	46	6.2.7	Reliability	55
5.1.3	Performance.....	46	6.2.8	Thermal Management.....	55
5.1.4	Thermal Expansion Mismatch	47	6.2.9	Vibration and Shock.....	56
5.1.5	Chip-on-Board/TAB	47	6.2.10	Simplified Cyclic Strain Considerations.....	56
5.2	Organic-Base Material P&IS	47	6.2.11	Power Consumption	56
5.2.1	Epoxy-Fiberglass Materials.....	47	6.2.12	Power Cycling	56
5.2.2	Polyimide-Fiberglass Materials.....	47	6.2.13	Warping and Rigidity.....	56
5.2.3	Epoxy Aramid Fiber Materials	47	6.2.14	Testing.....	57
5.2.4	Polyimide Aramid Fiber Materials	47	6.2.15	High Speed	57
5.2.5	Polyimide Quartz Materials	47	6.2.16	High Frequency	57
5.2.6	Fiberglass/Aramid Fiber Materials	48	6.2.17	EMI/RFI.....	57
5.2.7	Teflon® Fiberglass Materials	48	6.2.18	Parasitic Elements	59
5.2.8	Flexible-Dielectric Structures.....	48	6.2.19	ESD.....	59
5.2.9	Thermoplastic Resin P&I Structures	48	6.2.20	EOS.....	59
5.3	Non-Organic Base Materials.....	48	6.2.21	Commonality	59
5.3.1	Hybrid Circuits	48	6.2.22	Pin Count.....	59
5.3.2	Ceramic Printed Boards	48	6.2.23	Storage and Handling.....	60
5.4	Supporting-Plane P&I Structures.....	48	6.2.24	Safety and Handling.....	60
5.4.1	Printed Board Bonded to Support Plane (Metal or Non-Metal).....	48	6.3	Packaging Considerations	60
5.4.2	Sequentially-Processed Structures with Metal Support Plane.....	49	6.3.1	Density.....	60
5.4.3	Discrete-Wire Structures with Metal Support Plane	49	6.3.2	Gross Estimate.....	60
5.4.4	Flexible Printed Board with Metal Support Plane	49	6.3.3	Detail Estimate	60
5.5	Constraining Core P&I Structures	50	6.3.4	Final Design Review	61
5.5.1	Porcelainized-Metal (Metal Core) Structures	50	6.3.5	End Product Considerations.....	61
5.5.2	Printed Board With Constraining (not electrically functioning) Core	51	6.4	Performance, Reliability and Producibility	62
5.5.3	Printed Boards with Electrically-Functional Constraining Cores	51	6.5	CAD/CAM Relationships.....	62
5.5.4	Printed Board With Constraining Core.....	51	6.6	Testing Considerations	64
5.5.5	Compliant-Layer Structures	52	6.6.1	Design to Test.....	64
6.0	DESIGN PARAMETERS	52	6.6.2	Fan Out.....	64
6.1	General Considerations	52	6.7	P&IS Design Issues.....	64
6.1.1	Specifications.....	52	6.7.1	Through-the-Board	64
6.1.2	Design Responsibilities	54	6.7.2	Land Pattern Considerations	66
6.2	System Requirements	54	6.7.3	Mixed Mounting.....	73
6.2.1	Partitioning	54	6.7.4	Chip-on-Board Considerations.....	73
6.2.2	Mechanical Configurations.....	54	7.0	P&I STRUCTURE (P&IS) FABRICATION	74
			7.1	Organic Printed Boards.....	74
			7.2	Constraining Core P&IS	74
			7.2.1	Types.....	74
			7.2.2	Spray Coating Process	74
			7.2.3	Electrophoretic Deposition Process	74
			7.2.4	Fluidized Bed Process	75

7.2.5	Molding Process	75	8.5.2	Solder Preforms	101
7.3	Material Considerations	75	8.6	Component Placement.....	101
7.3.1	Incoming Tests.....	75	8.6.1	Through Hole Placement	102
7.3.2	Safety	75	8.6.2	Manual Techniques.....	103
7.3.3	Material Storage	75	8.6.3	Intermixed Technology.....	106
7.4	Process Flow and Control	76	8.7	Surface Mounting	108
7.4.1	Process Flow Charts	76	8.7.1	Manual Assembly	108
7.4.2	Process Control Environmental Conditions....	76	8.7.2	Automated Assembly	108
7.5	Fabricating Techniques	77	8.8	Chip-on-Board Placement	108
7.5.1	Parallel Processing for Multilayer Printed Boards (Blind and Buried Vias)	77	8.8.1	Low-Volume Equipment	109
7.5.2	Processing for Single-and Double- Sided Boards.....	80	8.8.2	Fully-Integrated Systems.....	110
7.5.3	Non-Organic Printed Board	80	8.9	Component Attachment	111
7.6	Quality Conformance Coupons.....	81	8.9.1	Soldering, General	111
7.6.1	Quantity and Location.....	81	8.9.2	Wave Soldering.....	111
7.6.2	Identification	81	8.9.3	Reflow Soldering	113
7.6.3	Tolerances	81	8.9.4	Adhesive Bonding	115
7.6.4	Lands and Holes.....	81	8.9.5	Wire Bonding	115
7.6.5	Conductors.....	82	8.10	Cleaning	117
7.6.6	Etched Letters.....	82	8.10.1	Post-soldering Cleaning.....	117
7.6.7	Number of Layers	82	8.10.2	Surface Mount Considerations.....	117
7.6.8	Coupon Length.....	82	8.11	Conformal Coating	119
7.6.9	Test Coupon Examples	82	8.11.1	Masking.....	119
8.0	ASSEMBLY PROCESSES	86	8.11.2	Application	120
8.1	General Considerations	86	8.11.3	Bake	120
8.1.1	P&IS Assembly Techniques	86	8.11.4	Handling	120
8.1.2	Epoxy Attachment	87	8.11.5	Results.....	120
8.1.3	Solderability.....	87	9.0	QUALITY ASSURANCE AND TESTING.....	120
8.1.4	Conformal Coating	87	9.1	Quality Assurance and Testing.....	120
8.2	Process Flow	88	9.1.1	Preassembly Assurance	121
8.2.1	Introduction.....	88	9.2	Solderability.....	121
8.3	Materials	88	9.2.1	Acceptable Solderability Criteria	121
8.3.1	Flux	88	9.2.2	Surface Solderability Tests.....	122
8.3.2	Solders	90	9.3	Quality Assurance Provisions	123
8.3.3	Adhesives.....	92	9.3.1	Materials Inspection	123
8.3.4	Conformal Coating	93	9.3.2	Quality Conformance Inspection	123
8.4	Component Preparation.....	94	9.4	Post Assembly Assurance.....	127
8.4.1	Through Hole Mounting	94	9.4.1	Visual Joint Inspection.....	127
8.4.2	Straight Through Leads.....	94	9.4.2	Verification Inspection.....	128
8.4.3	Performed Leads.....	95	9.4.3	Workmanship.....	128
8.4.4	Surface Mounting Leded Components	97	9.5	Mechanical and Electrical Testing	134
8.4.5	Surface Mounted Leadless Device	98	9.6	Solder Joint Mechanism of Failure.....	135
8.4.6	Connectors/sockets.....	99	9.7	Handling Electronic Assemblies	136
8.5	Solder Placement	100	9.7.1	Metal Fatigue Failure	137
8.5.1	Solder Paste Placement	100	9.7.2	Brittle Failure	138
			9.7.3	Overstress Conditions.....	138

9.7.4 Handling and Shipping Damage..... 138

10.0 MODIFICATION AND REPAIR..... 138

10.1 Basic Rules 138

10.2 Handling Electronic Assemblies 139

10.2.1 General Guidelines 139

10.2.2 Handling After Cleaning 139

10.2.3 Electrostatic Discharge (ESD) Damage Prevention 139

10.2.4 Electrical Overstress (EOS) Damage Prevention 139

10.2.5 Warning Labels..... 140

10.2.6 EOS/ESD Sensitivity Markings 140

10.2.7 Protective Methods 140

10.2.8 EOS/ESD Safe Work Station 141

10.3 General Modification/Repair Procedures..... 141

10.3.1 Cleaning 141

10.3.2 Identification of Coatings..... 141

10.3.3 Coating Removal..... 142

10.3.4 Legends and Markings 142

10.4 P&I Structure Modification/Repair..... 142

10.5 P&I Assembly Modification/Repair Methods 142

10.5.1 Removal and Replacement of Components 143

10.5.2 Heat Factors..... 143

10.5.3 Through-Hole Mounted Components 144

10.5.4 Surface Mounted Devices 145

10.5.5 Through-Hole and Surface Mounted Component Removal..... 147

10.5.6 Replacement of Surface Mounted Devices 148

Figure 4-5 Pin and hole locating feature..... 19

Figure 4-6 Axial leaded component 20

Figure 4-7 Radial lead (dipped) capacitor..... 20

Figure 4-8 Radial lead transistor can 20

Figure 4-9 Flat rectangular chip resistor 21

Figure 4-10 Chip resistor constructions 21

Figure 4-11 Multiple layer ceramic chip capacitor 22

Figure 4-12 Chip capacitor package 22

Figure 4-13 MELF body outlines..... 22

Figure 4-14 A chip inductor 22

Figure 4-15 Typical surface mount inductor..... 23

Figure 4-16 Surface mount cermet trimmer..... 23

Figure 4-17 "TO" can outline drawing..... 24

Figure 4-18 SOT-23 package..... 25

Figure 4-19 SOT-89 package..... 25

Figure 4-20 SOT-23 comparisons 25

Figure 4-21 SOT-143 dimensions 25

Figure 4-22 16-pin SO and SOL outline 26

Figure 4-23 Proposed JEDEC outline for SOJ packages... 27

Figure 4-24 Typical DIP outline 27

Figure 4-25 Typical SIP outline 27

Figure 4-26 Typical QUIP outline 28

Figure 4-27 Typical QUIL outline..... 28

Figure 4-28 Flatpack outline..... 28

Figure 4-29 Quad pack configuration..... 29

Figure 4-30 Typical ribbon leaded transistor..... 29

Figure 4-31 The 50-mil center JEDEC packages 30

Figure 4-32 Mounting compatibility of JEDEC packages ... 31

Figure 4-33 Features common to the 50-mil center packages..... 31

Figure 4-34 Type E package variations 32

Figure 4-35A Chip carrier land pattern design 32

Figure 4-35B Leadless ceramic chip carrier attached to a CTE-tailored P&I structure with solder columns..... 33

Figure 4-36 Square plastic chip carrier..... 34

Figure 4-37 Rectangular plastic chip carrier 35

Figure 4-38 Double row plastic chip carrier 36

Figure 4-39 Open-via chip carrier (OVCC) 37

Figure 4-40 149-pin array package 37

Figure 4-41 I/O density versus lead count..... 37

Figure 4-42 Surface mount connector land pattern criteria 39

Figure 4-43 Surface mount connector hold down features 39

Figure 4-44 Surface mounting socket 40

Figure 4-45 Section through socket solder contact 40

Figure 4-46 Screw down cover 41

Figure 4-47 Section through pressure-mounted socket..... 42

Figure 4-48 Section through through-hole mounting socket contact..... 42

Figures

Figure 3-1 Ideal connective length needed versus number of pins and package type (all dimensions in inches)..... 6

Figure 3-2 Cooling option combinations 8

Figure 3-3 Packaging and assembling integrated circuits (all dimensions in inches)..... 10

Figure 3-4 Semiconductor technology development..... 11

Figure 3-5 Gate density comparison (all dimensions in inches) 12

Figure 3-6 Packaging technology comparisons (all dimensions in inches)..... 12

Figure 3-7 Joint geometries 15

Figure 4-1 Interrelated package design factors 18

Figure 4-2 Matrix tray 19

Figure 4-3 Tube or magazine packaging 19

Figure 4-4 Bulk packaging 19

Figure 4-49	Surface-mount DIP socket.....	42	Figure 6-22	Land patterns for standard leadless chip carriers (LCC)	70
Figure 4-50	Pin grid array sockets.....	43	Figure 6-23	1.27 mm [0.050 in] pitch chip carrier site with "IL" fan-out for leadless type C.....	71
Figure 4-51	Leadless grid array socket	43	Figure 6-24	1.27 mm [0.050 in.] pitch chip carrier site with "II" fan out	71
Figure 4-52	D-subminiature surface mount connector	43	Figure 6-25	Modified fan out patterns.....	71
Figure 4-53	Surface mount receptacle.....	44	Figure 6-26	Peripheral fan out	72
Figure 4-54	Box-contact surface mount receptacle	44	Figure 6-27	Solid fan out.....	72
Figure 4-55	Surface mount header	44	Figure 6-28	High package density fan out.....	72
Figure 4-56	Surface mount card edge connector	44	Figure 6-29	Multilayer fabrication (standard parallel process with buried via layers)	72
Figure 5-1	Printed board bonded to supporting plane.....	49	Figure 6-30	Buried via on internal layer between 2.54 mm [0.100 in] centers through-vias.....	72
Figure 5-2	Sequentially-processed structure with supporting plane	49	Figure 7-1	Double-sided rigid printed board process flow chart	76
Figure 5-3	Discrete-wire structure with low-expansion metal support plane	50	Figure 7-2	Multilayer board process flow chart.....	77
Figure 5-4	Flexible printed board with metal support plane	50	Figure 7-3	Multilayer flexible printed board process flow chart	77
Figure 5-5	Printed board with supporting plane (not electrically-functional constraining core).....	51	Figure 7-4	Rigid-flex multilayer process flow chart.....	78
Figure 5-6	Multilayer P&I structure with copper-clad Invar power and ground planes (electrically-functional constraining cores).....	51	Figure 7-5	Non-organic printed board process flow chart.....	78
Figure 5-7	Balanced structure with constraining core not at neutral axis.....	52	Figure 7-6	Gang soldermask window	80
Figure 5-8	Balanced structure with constraining core on neutral axis	52	Figure 7-7	Individual soldermask windows	81
Figure 5-9	Compliant-layer P&I structure.....	52	Figure 7-8	A + B coupon (types 2 and 3)	83
Figure 6-1	Design flow chart	53	Figure 7-9	C coupon details.....	83
Figure 6-2	Productivity plan	54	Figure 7-10	D coupons details	83
Figure 6-3	Manufacturing cost vs. complexity of circuit....	55	Figure 7-11	E coupon details	84
Figure 6-4	P&I structure signal loop	58	Figure 7-12	F coupon details (type 3).....	84
Figure 6-5	Power ground interconnections	58	Figure 7-13	G coupon details.....	84
Figure 6-6	Decoupling capacitor placement	59	Figure 7-14	H coupon details.....	85
Figure 6-7	High I/O component decoupling capacitor design	59	Figure 7-15	J coupon details.....	85
Figure 6-8	Crosstalk situation	60	Figure 8-1	Minimum inside bend radius.....	95
Figure 6-9	Design N/C documentation options.....	63	Figure 8-2	Single in-line component	95
Figure 6-10	Clipped-land conductor routing (dimensions in inches)	65	Figure 8-3	Staggered hole pattern mounting. "MO" flat pack outline drawing (<i>only inches shown</i>).	96
Figure 6-11	Filletted land (dimensions in inches)	65	Figure 8-4	Through hole mounting. "MO" flat pack outline drawing.....	96
Figure 6-12	Typical one-conductor routing	66	Figure 8-5	Loop bends	96
Figure 6-13	Typical two-conductor routing	66	Figure 8-6	Axial-lead stress relief	96
Figure 6-14	Typical three-conductor routing	66	Figure 8-7	Stress relief leads	96
Figure 6-15	Staggered grid—3 lines/channel	66	Figure 8-8	Simple-offset preformed leads.....	96
Figure 6-16	Chip resistor.....	67	Figure 8-9	Dimple preformed leads	97
Figure 6-17	Land patterns for rectangular chip resistors....	67	Figure 8-10	Compound preformed leads	97
Figure 6-18	Outline of a small outline integrated circuit (SOIC).....	67	Figure 8-11	Combination preformed leads	97
Figure 6-19	Land pattern design for SOICs.....	68	Figure 8-12	Lead bend for surface mounting	97
Figure 6-20	Land patterns for square outline JEDEC premolded plastic J-led chip carriers.....	69	Figure 8-13	Lead bending requirements for surface mounting	97
Figure 6-21	Section view of plastic leaded chip carrier (PLCC).....	69	Figure 8-14	SO-16 package drawings typical dimensions.....	98
			Figure 8-15	Typical SOT packages.....	99
			Figure 8-16	Modifying DIP for surface mounting	99

Figure 8-17 Gull wing lead for SIP type component..... 99

Figure 8-18 Criteria for lead attachment to leadless type A (leadless type B) 99

Figure 8-19 Example of assembly process..... 100

Figure 8-20 Single-sided boards 102

Figure 8-21 Double-sided/multilayer boards 102

Figure 8-22 Components mounted over conductors 103

Figure 8-23 Alignment/boundaries 104

Figure 8-24 Horizontally mounted components 104

Figure 8-25 Clearance..... 104

Figure 8-26 Vertical mounted axial lead components..... 105

Figure 8-27 Component types through boards 105

Figure 8-28 Individual work station 106

Figure 8-29 Multiple work station 106

Figure 8-30 Assembly station..... 106

Figure 8-31 Programmable assembly station 106

Figure 8-32 Placement machine considerations..... 107

Figure 8-33 Panel assembly tooling holes..... 107

Figure 8-34 Positive symbol machine correction 107

Figure 8-35 Chip placement..... 108

Figure 8-36 Surface mount component types..... 109

Figure 8-37 Preferred mounting orientations 109

Figure 8-38 Clip carrier alignment..... 109

Figure 8-39 Typical low-volume COB chip handling systems 110

Figure 8-40 COB chip handling system block diagram 111

Figure 8-41 Fully-integrated COB assembly system..... 111

Figure 8-42 Mechanics of thermocompression ball wire bonding 116

Figure 8-43 Thermocompression stitch wire bonding 117

Figure 8-44 Mechanics of ultrasonic bond wiring..... 118

Figure 8-45 Mechanics of thermosonic wire bonding 119

Figure 9-1 Effectiveness of solder wetting of plated-through holes 122

Figure 9-2 Edge dip solderability test 122

Figure 9-3 Sketch of specimen holder and timing needle for performing the rotary dip test (time solder rise test)..... 123

Figure 9-4 Zero defects graphic illustration 125

Figure 9-5 Class 3 Defect Classification Criteria 126

Figure 9-6 Flat ribbon solder joint 129

Figure 9-7 Round or coined leads 130

Figure 9-8 J and V lead solder joints..... 130

Figure 9-9 Rectangular or square end component solder joints..... 131

Figure 9-10 Cylindrical component solder joint..... 131

Figure 9-11 Bottom only terminations 132

Figure 9-12 I-beam solder joint 132

Figure 9-13 Leadless chip carriers with castellated terminations—joint geometrical description... 133

Figure 9-14 Leadless chip carriers with castellated terminations—joint fillet appearance 133

Figure 9-15 Acceptable—handle with clean hands on board edges..... 137

Figure 9-16 Not recommended—hands placed on conductive patterns and components..... 137

Figure 9-17 Preferred—handle printed board assembly with clean cloth or rubber gloves on printed board edges..... 137

Figure A MIL-STD-129H symbol 140

Figure B EIA RS-471 symbol 140

Figure C No official status 140

Figure D EOS/ESD Association & ITT Research Institute 140

Figure 10-2 Typical manufacturing work station 141

Figure 10-3 R&R system having a very high degree of air/gas flow control 146

Figure 10-4 Commercially available surface mount component R&R system..... 146

Figure 10-5 Single-sided hot air component remover 146

Figure 10-6 Double-sided hot air component remover 146

Figure 10-7 Commercial hot air component remover 147

Figure 10-8 Small hot air jet lap solder joint component removal 147

Figure 10-9 Lap reflow soldering tool used for component removal 147

Figure 10-10 Hot gripper—hand force component remover..... 147

Figure 10-11 Thermal tweezer—finger tip controlled component remover..... 148

Tables

Table 3-1 System Design Sequence..... 5

Table 3-2 Connectivity Capacity Requirements for DIPs and Small Chip Carriers (Dimensions only in inches) 11

Table 3-3 Relative Size of Packaging Techniques..... 13

Table 3-4 A Comparison of Integrated Circuit Packaging Technologies..... 13

Table 3-5 Joint Geometry Benefits and Problems 15

Table 4-1 Film Resistor Characteristics 23

Table 4-2 Typical Integrated Circuit Packages..... 24

Table 4-3 JEDEC Ceramic Sizes and Fine Pitch Terminal Counts..... 32

Table 5-1 Packaging and Interconnecting Structure Comparison 45

Table 5-2 P&L Structure Selection Considerations..... 46

Table 5-3 P&L Structure Material Properties..... 46

Table 6-1 Shock and Vibration Parameters 56

Table 6-2 Table of General COB Design Guidelines 73

Table 7-1 Areas of Concern 74

Table 7-2 Organic Printed Board Processes..... 75

Table 7-3 Coupon Frequency Recommendations, Design Complexity Class, Coupon Frequency Recommendations..... 82

Table 8-1	Assembly Process Flow Comparison	89	Table 9-4	Examples of Some of the Minor Defects	127
Table 8-2	Solder Alloys.....	90	Table 9-5	Dimensional Criteria—Leadless Chip Carriers with Castellated Terminations Dimensions in mm [in.] — (Minimum Values Apply).....	133
Table 8-3	Solder-Bath Contaminant Limits	91	Table 9-6	Cyclic Fatigue Testing	134
Table 8-4	Various Bonding Adhesive Types.....	93	Table 9-7	Typical Fatigue Test Parameters.....	134
Table 8-5	Epoxy Device—Attachment Materials.....	93	Table 9-8	Environmental Tests	135
Table 8-6	Component Placement Force	109	Table 9-9	Summary of Basic Analytical Techniques	136
Table 9-1	Quality Conformance Testing and Frequency.....	124	Table 10-1	Approximate ESD Damage Range for Some Components	139
Table 9-2	Zero Defect Sampling Plan for Equipment Classes per Lot Size	125			
Table 9-3	Example of Several Major Defects	127			

Guidelines for Component Packaging and Interconnection with Emphasis on Surface Mounting

1.0 INTRODUCTION

Today's advanced electronic designs combine miniaturization and weight savings with high performance and low power consumption. To achieve all this, electronic assemblers often use surface mount technology, either alone or in combination with other sophisticated attachment processes.

This document examines key issues in advanced packaging techniques. These guidelines provide information on what type of parts are available, the techniques and processes necessary for their proper use, possible advantages, disadvantages or problems, how to start implementation, and where to find additional information. Since no one technology will provide all of the answers, the guidelines establish criteria for intermixing the processes, and define the necessary steps for producing quality electronic equipment. When other specific documents are cited, they should be reviewed for the current requirements. Where appropriate, sections from other IPC documents have been excerpted.

1.1 Scope This document provides guidelines for surface mounting electronic parts, and for intermixing surface and through-the-board mounting techniques. In addition, it describes the types of materials and interconnection substrates necessary for sophisticated electronic assemblies.

1.2 Purpose This document is intended to aid the designer in designing a manufacturable product by providing information on processing and on various types of substrate and joining materials.

The substrate physical and electrical characteristics and their compatibility for surface mounting are discussed. Land pattern designs, solder joint configurations, rework, and repair are also covered.

Adherence to the guidelines set forth in this document will generally assure adequate reliability for the majority of applications; however, more rigid requirements may be appropriate for more critical applications.

1.3 Classification When appropriate, this guideline will refer to three classes of component mounting complexity which reflect progressive increases in sophistication of tooling, assembly and joining techniques, and cost. These classes are as follows:

- A) Simple assembly techniques for through-the-board component mounting;
- B) Moderate assembly techniques for surface component mounting

- C) Complex assembly techniques for intermixing through-the-board and surface mounting on the same assembly.

Classification of component mounting complexity should not be confused with the performance classification of end-item use, as referenced in other IPC documents, which refers to Class 1) consumer products, Class 2) general industrial and Class 3) high reliability equipment types.

In addition to component mounting classification, a type designation may be specified for components mounted on one or both sides of the packaging and interconnecting structure:

Type 1 Components mounted on one side only;

Type 2 Components on both sides.

Type 2 is limited to only class B or C assemblies. Class and type designations help establish communication between design, manufacturing and assembly disciplines, as well as identify the precision and processing steps needed to assemble the board.

Any component mounting class and type may be applied to any of the end-product equipment classifications. For example, a consumer product designed to meet Class 1 requirements could have component mounting complexity Class A, B or C with components on either one or both sides of the board (Type 1 or 2).

1.4 Terms and Definitions The definition of terms used herein shall be in accordance with IPC-T-50 and the following: *Note:* Any definition denoted with an asterisk (*) is a reprint of the definition in IPC-T-50.

1.4.1 *Castellations Recessed metallized features on the edges of a chip carrier which interconnect conducting surfaces or planes within or on the chip carrier.

1.4.2 *Chip Carrier A low-profile rectangular component package, usually square, whose semiconductor chip cavity or mounting area is a large fraction of the package size and whose external connections are usually on all four sides of the package.

1.4.3 *Coefficient of Thermal Expansion Mismatch (Δ CTE) The difference between the coefficients of thermal expansion of two components, i.e., the difference in linear thermal expansion per unit change in temperature. (This term is not to be confused with Thermal Expansion Mismatch.)